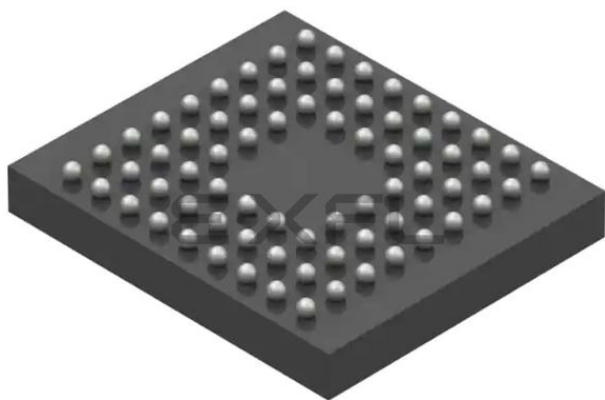




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Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, SWPMI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, LCD, PWM, WDT
Number of I/O	57
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	72-UFBGA, WLCSP
Supplier Device Package	72-WLCSP (4.41x3.76)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l476jey6tr

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Table 2. STM32L476xx family device features and peripheral counts (continued)

Peripheral	STM32L476 Zx	STM32L476 Qx	STM32L476 Vx	STM32L476 Mx	STM32L476 Jx	STM32L476 Rx
Max. CPU frequency	80 MHz					
Operating voltage	1.71 to 3.6 V					
Operating temperature	Ambient operating temperature: -40 to 85 °C / -40 to 105 °C / -40 to 125 °C Junction temperature: -40 to 105 °C / -40 to 125 °C / -40 to 130 °C					
Packages	LQFP144	UFBGA132	LQFP100	WLCSP81	WLCSP72	LQFP64

- For the LQFP100 package, only FMC Bank1 is available. Bank1 can only support a multiplexed NOR/PSRAM memory using the NE1 Chip Select.

3.9.3 Voltage regulator

Two embedded linear voltage regulators supply most of the digital circuitries: the main regulator (MR) and the low-power regulator (LPR).

- The MR is used in the Run and Sleep modes and in the Stop 0 mode.
- The LPR is used in Low-Power Run, Low-Power Sleep, Stop 1 and Stop 2 modes. It is also used to supply the 32 Kbyte SRAM2 in Standby with RAM2 retention.
- Both regulators are in power-down in Standby and Shutdown modes: the regulator output is in high impedance, and the kernel circuitry is powered down thus inducing zero consumption.

The ultralow-power STM32L476xx supports dynamic voltage scaling to optimize its power consumption in run mode. The voltage from the Main Regulator that supplies the logic (VCORE) can be adjusted according to the system's maximum operating frequency.

There are two power consumption ranges:

- Range 1 with the CPU running at up to 80 MHz.
- Range 2 with a maximum CPU frequency of 26 MHz. All peripheral clocks are also limited to 26 MHz.

The VCORE can be supplied by the low-power regulator, the main regulator being switched off. The system is then in Low-power run mode.

- Low-power run mode with the CPU running at up to 2 MHz. Peripherals with independent clock can be clocked by HSI16.

3.9.4 Low-power modes

The ultra-low-power STM32L476xx supports seven low-power modes to achieve the best compromise between low-power consumption, short startup time, available peripherals and available wakeup sources:

Table 4. STM32L476 modes overview (continued)

Mode	Regulator ⁽¹⁾	CPU	Flash	SRAM	Clocks	DMA & Peripherals ⁽²⁾	Wakeup source	Consumption ⁽³⁾	Wakeup time
Stop 1	LPR	No	Off	ON	LSE LSI	BOR, PVD, PVM RTC, LCD,IWDG COMPx (x=1,2) DACx (x=1,2) OPAMPx (x=1,2) USARTx (x=1...5) ⁽⁶⁾ LPUART1 ⁽⁶⁾ I2Cx (x=1...3) ⁽⁷⁾ LPTIMx (x=1,2) *** All other peripherals are frozen.	Reset pin, all I/Os BOR, PVD, PVM RTC, LCD,IWDG COMPx (x=1..2) USARTx (x=1...5) ⁽⁶⁾ LPUART1 ⁽⁶⁾ I2Cx (x=1...3) ⁽⁷⁾ LPTIMx (x=1,2) OTG_FS ⁽⁸⁾ SWPMI1 ⁽⁹⁾	6.6 μ A w/o RTC 6.9 μ A w RTC	4 μ s in SRAM 6 μ s in Flash
Stop 2	LPR	No	Off	ON	LSE LSI	BOR, PVD, PVM RTC, LCD,IWDG COMPx (x=1..2) I2C3 ⁽⁷⁾ LPUART1 ⁽⁶⁾ LPTIM1 *** All other peripherals are frozen.	Reset pin, all I/Os BOR, PVD, PVM RTC, LCD,IWDG COMPx (x=1..2) I2C3 ⁽⁷⁾ LPUART1 ⁽⁶⁾ LPTIM1	1.1 μ A w/o RTC 1.4 μ A w/RTC	5 μ s in SRAM 7 μ s in Flash

Table 6. STM32L476xx peripherals interconnect matrix (continued)

Interconnect source	Interconnect destination	Interconnect action	Run	Sleep	Low-power run	Low-power sleep	Stop 0 / Stop 1	Stop 2
GPIO	TIMx	External trigger	Y	Y	Y	Y	-	-
	LPTIMERx	External trigger	Y	Y	Y	Y	Y	Y ⁽¹⁾
	ADCx DACx DFSDM	Conversion external trigger	Y	Y	Y	Y	-	-

1. LPTIM1 only.

3.26 Inter-integrated circuit interface (I2C)

The device embeds 3 I2C. Refer to [Table 11: I2C implementation](#) for the features implementation.

The I²C bus interface handles communications between the microcontroller and the serial I²C bus. It controls all I²C bus-specific sequencing, protocol, arbitration and timing.

The I2C peripheral supports:

- I²C-bus specification and user manual rev. 5 compatibility:
 - Slave and master modes, multimaster capability
 - Standard-mode (Sm), with a bitrate up to 100 kbit/s
 - Fast-mode (Fm), with a bitrate up to 400 kbit/s
 - Fast-mode Plus (Fm+), with a bitrate up to 1 Mbit/s and 20 mA output drive I/Os
 - 7-bit and 10-bit addressing mode, multiple 7-bit slave addresses
 - Programmable setup and hold times
 - Optional clock stretching
- System Management Bus (SMBus) specification rev 2.0 compatibility:
 - Hardware PEC (Packet Error Checking) generation and verification with ACK control
 - Address resolution protocol (ARP) support
 - SMBus alert
- Power System Management Protocol (PMBus™) specification rev 1.1 compatibility
- Independent clock: a choice of independent clock sources allowing the I2C communication speed to be independent from the PCLK reprogramming. Refer to [Figure 3: Clock tree](#).
- Wakeup from Stop mode on address match
- Programmable analog and digital noise filters
- 1-byte buffer with DMA capability

Table 11. I2C implementation

I2C features ⁽¹⁾	I2C1	I2C2	I2C3
Standard-mode (up to 100 kbit/s)	X	X	X
Fast-mode (up to 400 kbit/s)	X	X	X
Fast-mode Plus with 20mA output drive I/Os (up to 1 Mbit/s)	X	X	X
Programmable analog and digital noise filters	X	X	X
SMBus/PMBus hardware support	X	X	X
Independent clock	X	X	X
Wakeup from Stop 0 / Stop 1 mode on address match	X	X	X
Wakeup from Stop 2 mode on address match	-	-	X

1. X: supported

Table 15. STM32L476xxSTM32L476xx pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	WLCSP72	WLCSP81	LQFP100	UFBGA132	LQFP144					Alternate functions	Additional functions
-	-	-	20	-	31	VREF-	S	-	-	-	-
12	G9	G9	-	J1	-	VSSA/VREF-	-	-	-	-	-
-	G8	G8	21	L1	32	VREF+	S	-	-	-	VREFBUF_OUT
-	H9	H9	22	M1	33	VDDA	S	-	-	-	-
13	-	-	-	-	-	VDDA/VREF+	S	-	-	-	-
14	H8	H8	23	L2	34	PA0	I/O	FT_a	-	TIM2_CH1, TIM5_CH1, TIM8_ETR, USART2_CTS, UART4_TX, SAI1_EXTCLK, TIM2_ETR, EVENTOUT	OPAMP1_VINP, ADC12_IN5, RTC_TAMP 2/WKUP1
-	-	-	-	M3	-	OPAMP1_VINM	I	TT	-	-	-
15	G4	G4	24	M2	35	PA1	I/O	FT_la	-	TIM2_CH2, TIM5_CH2, USART2_RTS_DE, UART4_RX, LCD_SEG0, TIM15_CH1N, EVENTOUT	OPAMP1_VINM, ADC12_IN6
16	G6	G6	25	K3	36	PA2	I/O	FT_la	-	TIM2_CH3, TIM5_CH3, USART2_TX, LCD_SEG1, SAI2_EXTCLK, TIM15_CH1, EVENTOUT	ADC12_IN7, WKUP4/ LSCO
17	H7	H7	26	L3	37	PA3	I/O	TT	-	TIM2_CH4, TIM5_CH4, USART2_RX, LCD_SEG2, TIM15_CH2, EVENTOUT	OPAMP1_VOUT, ADC12_IN8
18	J9	J9	27	E3	38	VSS	S	-	-	-	-
19	J8	J8	28	H3	39	VDD	S	-	-	-	-
20	G5	G5	29	J4	40	PA4	I/O	TT_a	-	SPI1_NSS, SPI3_NSS, USART2_CK, SAI1_FS_B, LPTIM2_OUT, EVENTOUT	ADC12_IN9, DAC1_OUT1
21	H6	H6	30	K4	41	PA5	I/O	TT_a	-	TIM2_CH1, TIM2_ETR, TIM8_CH1N, SPI1_SCK, LPTIM2_ETR, EVENTOUT	ADC12_IN10, DAC1_OUT2
22	H5	H5	31	L4	42	PA6	I/O	FT_la	-	TIM1_BKIN, TIM3_CH1, TIM8_BKIN, SPI1_MISO, USART3_CTS, QUADSPI_BK1_IO3, LCD_SEG3, TIM1_BKIN_COMP2, TIM8_BKIN_COMP2, TIM16_CH1, EVENTOUT	OPAMP2_VINP, ADC12_IN11

Table 22. General operating conditions (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
T _A	Ambient temperature for the suffix 6 version	Maximum power dissipation	−40	85	°C
		Low-power dissipation ⁽⁵⁾	−40	105	
	Ambient temperature for the suffix 7 version	Maximum power dissipation	−40	105	
		Low-power dissipation ⁽⁵⁾	−40	125	
	Ambient temperature for the suffix 3 version	Maximum power dissipation	−40	125	
		Low-power dissipation ⁽⁵⁾	−40	130	
T _J	Junction temperature range	Suffix 6 version	−40	105	°C
		Suffix 7 version	−40	125	
		Suffix 3 version	−40	130	

1. When RESET is released functionality is guaranteed down to V_{BOR0} Min.
2. This formula has to be applied only on the power supplies related to the IO structure described by the pin definition table. Maximum I/O input voltage is the smallest value between MIN(V_{DD}, V_{DDA}, V_{DDIO2}, V_{DDUSB}, V_{LCD})+3.6 V and 5.5V.
3. For operation with voltage higher than Min (V_{DD}, V_{DDA}, V_{DDIO2}, V_{DDUSB}, V_{LCD}) +0.3 V, the internal Pull-up and Pull-Down resistors must be disabled.
4. If T_A is lower, higher P_D values are allowed as long as T_J does not exceed T_{Jmax} (see [Section 7.7: Thermal characteristics](#)).
5. In low-power dissipation state, T_A can be extended to this range as long as T_J does not exceed T_{Jmax} (see [Section 7.7: Thermal characteristics](#)).

6.3.2 Operating conditions at power-up / power-down

The parameters given in [Table 23](#) are derived from tests performed under the ambient temperature condition summarized in [Table 22](#).

Table 23. Operating conditions at power-up / power-down

Symbol	Parameter	Conditions	Min	Max	Unit
t _{VDD}	V _{DD} rise time rate	-	0	∞	μs/V
	V _{DD} fall time rate		10	∞	
t _{VDDA}	V _{DDA} rise time rate	-	0	∞	
	V _{DDA} fall time rate		10	∞	
t _{VDDUSB}	V _{DDUSB} rise time rate	-	0	∞	
	V _{DDUSB} fall time rate		10	∞	
t _{VDDIO2}	V _{DDIO2} rise time rate	-	0	∞	
	V _{DDIO2} fall time rate		10	∞	

6.3.3 Embedded reset and power control block characteristics

The parameters given in [Table 24](#) are derived from tests performed under the ambient temperature conditions summarized in [Table 22: General operating conditions](#).

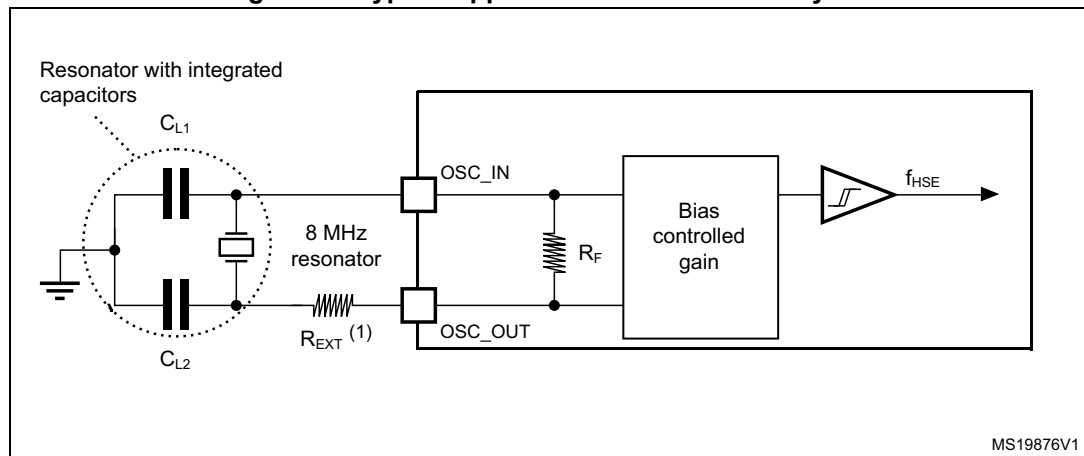
Table 34. Current consumption in Stop 2 mode (continued)

Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (Stop 2 with RTC)	Supply current in Stop 2 mode, RTC enabled	RTC clocked by LSI, LCD disabled	1.8 V	1.42	4.04	15	34.9	77.2	3.1	10	38	87	193	μA
			2.4 V	1.5	4.22	15.4	35.7	79.2	3.2	11	39	89	198	
			3 V	1.64	4.37	15.8	36.7	81.4	3.4	11	40	92	204	
			3.6 V	1.79	4.65	16.6	38.4	85.4	3.6	12	42	96	214	
		RTC clocked by LSI, LCD enabled ⁽³⁾	1.8 V	1.53	4.07	15.1	35.1	77.4	3.3	10	38	88	194	
			2.4 V	1.62	4.32	15.5	35.9	79.5	3.4	11	39	90	199	
			3 V	1.69	4.43	15.9	36.8	81.7	3.5	11	40	92	204	
			3.6 V	1.86	4.65	16.7	38.5	85.5	3.7	12	42	96	214	
		RTC clocked by LSE bypassed at 32768Hz, LCD disabled	1.8 V	1.5	4.13	15.2	35.3	77.6	3.2	10	38	88	194	
			2.4 V	1.63	4.33	15.6	36	79.6	3.4	11	39	90	199	
			3 V	1.79	4.55	16.1	37	81.8	3.6	11	40	93	205	
			3.6 V	2.04	4.9	16.8	38.7	85.6	3.9	12	42	97	214	
		RTC clocked by LSE quartz ⁽⁴⁾ in low drive mode, LCD disabled	1.8 V	1.43	3.99	14.7	35	-	3.2	10	37	88	-	
			2.4 V	1.54	4.11	15	35.8	-	3.3	10	38	90	-	
			3 V	1.67	4.29	15.5	36.7	-	3.4	11	39	92	-	
			3.6 V	1.87	4.57	16.2	38.3	-	3.7	11	41	96	-	
I _{DD} (wakeup from Stop2)	Supply current during wakeup from Stop 2 mode	Wakeup clock is MSI = 48 MHz, voltage Range 1. See ⁽⁵⁾ .	3 V	1.9	-	-	-	-	-					mA
		Wakeup clock is MSI = 4 MHz, voltage Range 2. See ⁽⁵⁾ .	3 V	2.24	-	-	-	-						
		Wakeup clock is HSI16 = 16 MHz, voltage Range 1. See ⁽⁵⁾ .	3 V	2.1	-	-	-	-						

1. Guaranteed by characterization results, unless otherwise specified.

Note: For information on selecting the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

Figure 18. Typical application with an 8 MHz crystal



1. R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal resonator oscillator. All the information given in this paragraph are based on design simulation results obtained with typical external components specified in [Table 46](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 46. LSE oscillator characteristics ($f_{LSE} = 32.768$ kHz)⁽¹⁾

Symbol	Parameter	Conditions ⁽²⁾	Min	Typ	Max	Unit
$I_{DD(LSE)}$	LSE current consumption	LSEDRV[1:0] = 00 Low drive capability	-	250	-	nA
		LSEDRV[1:0] = 01 Medium low drive capability	-	315	-	
		LSEDRV[1:0] = 10 Medium high drive capability	-	500	-	
		LSEDRV[1:0] = 11 High drive capability	-	630	-	
$G_{m_{critmax}}$	Maximum critical crystal gm	LSEDRV[1:0] = 00 Low drive capability	-	-	0.5	$\mu A/V$
		LSEDRV[1:0] = 01 Medium low drive capability	-	-	0.75	
		LSEDRV[1:0] = 10 Medium high drive capability	-	-	1.7	
		LSEDRV[1:0] = 11 High drive capability	-	-	2.7	
$t_{SU(LSE)}^{(3)}$	Startup time	V_{DD} is stabilized	-	2	-	s

Table 50. PLL, PLLSAI1, PLLSAI2 characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{PLL_IN}}$	PLL input clock ⁽²⁾	-	4	-	16	MHz
	PLL input clock duty cycle	-	45	-	55	%
$f_{\text{PLL_P_OUT}}$	PLL multiplier output clock P	Voltage scaling Range 1	2.0645	-	80	MHz
		Voltage scaling Range 2	2.0645	-	26	
$f_{\text{PLL_Q_OUT}}$	PLL multiplier output clock Q	Voltage scaling Range 1	8	-	80	MHz
		Voltage scaling Range 2	8	-	26	
$f_{\text{PLL_R_OUT}}$	PLL multiplier output clock R	Voltage scaling Range 1	8	-	80	MHz
		Voltage scaling Range 2	8	-	26	
$f_{\text{VCO_OUT}}$	PLL VCO output	Voltage scaling Range 1	64	-	344	MHz
		Voltage scaling Range 2	64	-	128	
t_{LOCK}	PLL lock time	-	-	15	40	μs
Jitter	RMS cycle-to-cycle jitter	System clock 80 MHz	-	40	-	$\pm\text{ps}$
	RMS period jitter		-	30	-	
$I_{\text{DD}}(\text{PLL})$	PLL power consumption on V_{DD} ⁽¹⁾	VCO freq = 64 MHz	-	150	200	μA
		VCO freq = 96 MHz	-	200	260	
		VCO freq = 192 MHz	-	300	380	
		VCO freq = 344 MHz	-	520	650	

1. Guaranteed by design.

2. Take care of using the appropriate division factor M to obtain the specified PLL input clock values. The M factor is shared between the 3 PLLs.

Table 60. I/O AC characteristics⁽¹⁾⁽²⁾ (continued)

Speed	Symbol	Parameter	Conditions	Min	Max	Unit
10	Fmax	Maximum frequency	C=50 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	50	MHz
			C=50 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	25	
			C=50 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	5	
			C=10 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	100 ⁽³⁾	
			C=10 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	37.5	
			C=10 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	5	
	Tr/Tf	Output rise and fall time	C=50 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	5.8	ns
			C=50 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	11	
			C=50 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	28	
			C=10 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	2.5	
			C=10 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	5	
			C=10 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	12	
11	Fmax	Maximum frequency	C=30 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	120 ⁽³⁾	MHz
			C=30 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	50	
			C=30 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	10	
			C=10 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	180 ⁽³⁾	
			C=10 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	75	
			C=10 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	10	
	Tr/Tf	Output rise and fall time	C=30 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	3.3	ns
			C=30 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	6	
			C=30 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	16	
Fm+	Fmax	Maximum frequency	C=50 pF, 1.6 V ≤ V _{DDIOx} ≤ 3.6 V	-	1	MHz
	Tf	Output fall time ⁽⁴⁾		-	5	ns

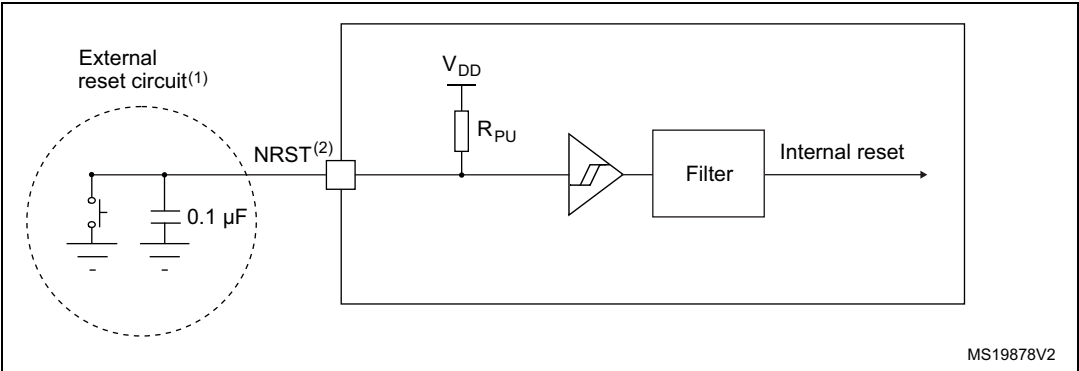
1. The I/O speed is configured using the OSPEEDRy[1:0] bits. The Fm+ mode is configured in the SYSCFG_CFGR1 register. Refer to the RM0351 reference manual for a description of GPIO Port configuration register.

2. Guaranteed by design.

3. This value represents the I/O capability but the maximum system frequency is limited to 80 MHz.

4. The fall time is defined between 70% and 30% of the output waveform accordingly to I²C specification.

Figure 24. Recommended NRST pin protection



1. The reset network protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the $V_{IL(NRST)}$ max level specified in [Table 61: NRST pin characteristics](#). Otherwise the reset will not be taken into account by the device.

6.3.16 Analog switches booster

Table 62. Analog switches booster characteristics⁽¹⁾

Symbol	Parameter	Min	Typ	Max	Unit
V_{DD}	Supply voltage	1.62	-	3.6	V
V_{BOOST}	Boost supply	2.7	-	4	
$t_{SU(BOOST)}$	Booster startup time	-	-	240	µs
$I_{DD(BOOST)}$	Booster consumption for $1.62\text{ V} \leq V_{DD} \leq 2.0\text{ V}$	-	-	250	µA
	Booster consumption for $2.0\text{ V} \leq V_{DD} \leq 2.7\text{ V}$	-	-	500	
	Booster consumption for $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	-	900	

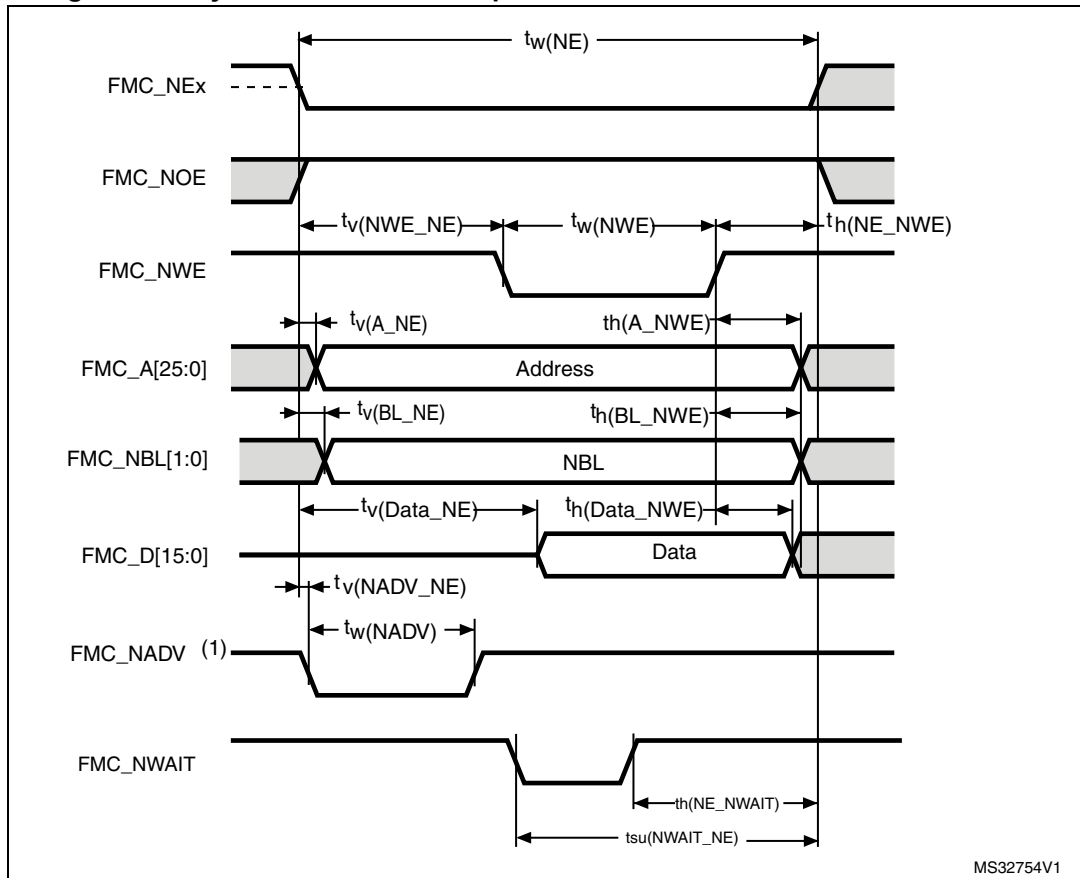
1. Guaranteed by design.

6.3.18 Digital-to-Analog converter characteristics

Table 69. DAC characteristics⁽¹⁾

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V _{DDA}	Analog supply voltage for DAC ON	-		1.8	-	3.6	V
V _{REF+}	Positive reference voltage	-		1.8	-	V _{DDA}	
V _{REF-}	Negative reference voltage	-		V _{SSA}			
R _L	Resistive load	DAC output buffer ON	connected to V _{SSA}	5	-	-	kΩ
			connected to V _{DDA}	25	-	-	
R _O	Output Impedance	DAC output buffer OFF		9.6	11.7	13.8	kΩ
R _{BON}	Output impedance sample and hold mode, output buffer ON	DAC output buffer ON	V _{DD} = 2.7 V	-	-	2	kΩ
			V _{DD} = 2.0 V	-	-	3.5	
R _{BOFF}	Output impedance sample and hold mode, output buffer OFF	DAC output buffer OFF	V _{DD} = 2.7 V	-	-	16.5	kΩ
			V _{DD} = 2.0 V	-	-	18.0	
C _L	Capacitive load	DAC output buffer ON		-	-	50	pF
C _{SH}		Sample and hold mode		-	0.1	1	μF
V _{DAC_OUT}	Voltage on DAC_OUT output	DAC output buffer ON		0.2	-	V _{REF+} – 0.2	V
		DAC output buffer OFF		0	-	V _{REF+}	
t _{SETTLING}	Settling time (full scale: for a 12-bit code transition between the lowest and the highest input codes when DAC_OUT reaches final value ±0.5LSB, ±1 LSB, ±2 LSB, ±4 LSB, ±8 LSB)	Normal mode DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ	±0.5 LSB	-	1.7	3	μs
			±1 LSB	-	1.6	2.9	
			±2 LSB	-	1.55	2.85	
			±4 LSB	-	1.48	2.8	
			±8 LSB	-	1.4	2.75	
		Normal mode DAC output buffer OFF, ±1LSB, CL = 10 pF		-	2	2.5	
t _{WAKEUP} ⁽²⁾	Wakeup time from off state (setting the ENx bit in the DAC Control register) until final value ±1 LSB	Normal mode DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ		-	4.2	7.5	μs
		Normal mode DAC output buffer OFF, CL ≤ 10 pF		-	2	5	
PSRR	V _{DDA} supply rejection ratio	Normal mode DAC output buffer ON CL ≤ 50 pF, RL = 5 kΩ, DC		-	-80	-28	dB

1. Guaranteed by design.
2. LCD enabled with 3 V internal step-up active, 1/8 duty, 1/4 bias, division ratio= 64, all pixels active, no LCD connected.

Figure 38. Asynchronous non-multiplexed SRAM/PSRAM/NOR write waveforms**Table 92. Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings⁽¹⁾⁽²⁾**

Symbol	Parameter	Min	Max	Unit
$t_w(NE)$	FMC_NE low time	$3T_{HCLK}-1$	$3T_{HCLK}+2$	ns
$t_v(NWE_NE)$	FMC_NEx low to FMC_NWE low	$T_{HCLK}-0.5$	$T_{HCLK}+1.5$	
$t_w(NWE)$	FMC_NWE low time	$T_{HCLK}-1$	$T_{HCLK}+1$	
$t_h(NE_NWE)$	FMC_NWE high to FMC_NE high hold time	$T_{HCLK}-0.5$	-	
$t_v(A_NE)$	FMC_NEx low to FMC_A valid	-	0	
$t_h(A_NWE)$	Address hold time after FMC_NWE high	$T_{HCLK}-1$	-	
$t_v(BL_NE)$	FMC_NEx low to FMC_NBL valid	-	1.5	
$t_h(BL_NWE)$	FMC_NBL hold time after FMC_NWE high	$T_{HCLK}-0.5$	-	
$t_v(Data_NE)$	Data to FMC_NEx low to Data valid	-	$T_{HCLK}+4$	
$t_h(Data_NWE)$	Data hold time after FMC_NWE high	$T_{HCLK}+1$	-	
$t_v(NADV_NE)$	FMC_NEx low to FMC_NADV low	-	1	
$t_w(NADV)$	FMC_NADV low time	-	$T_{HCLK}+0.5$	

1. CL = 30 pF.

2. Guaranteed by characterization results.

Figure 42. Synchronous multiplexed PSRAM write timings

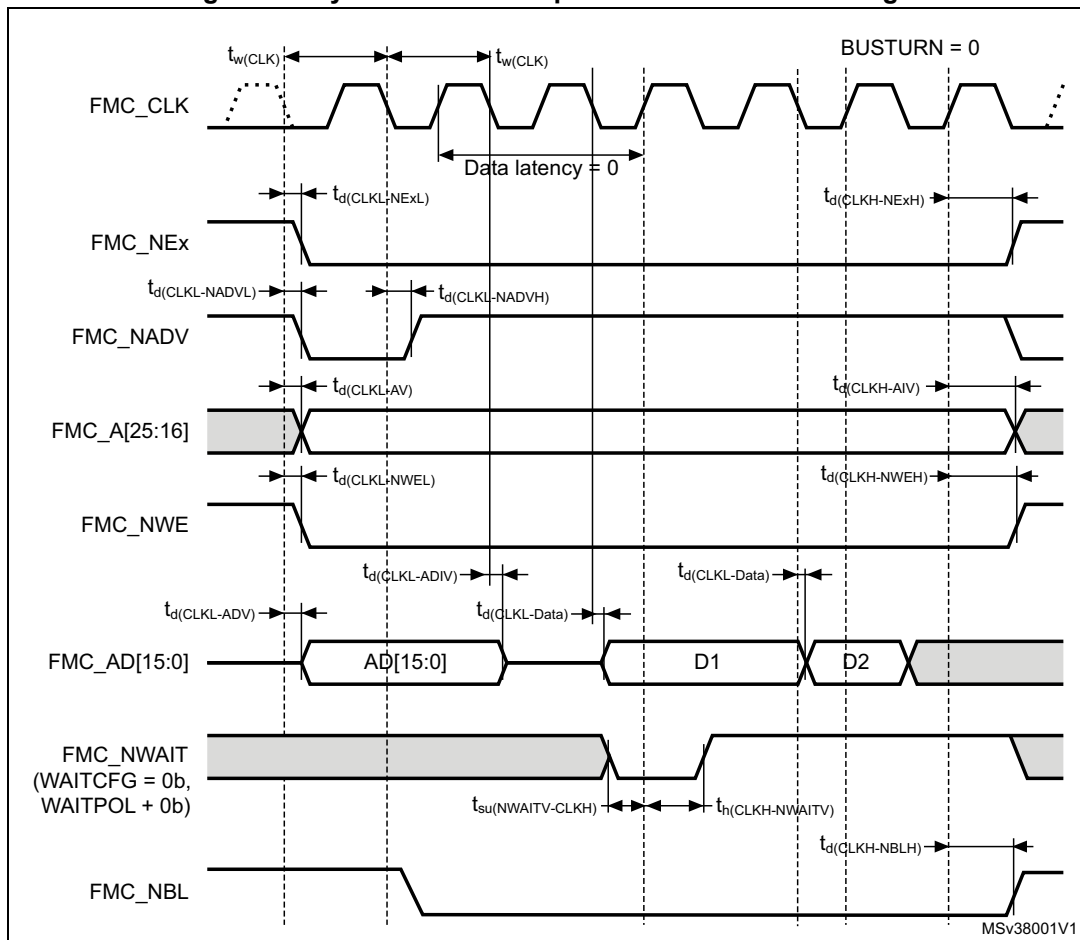
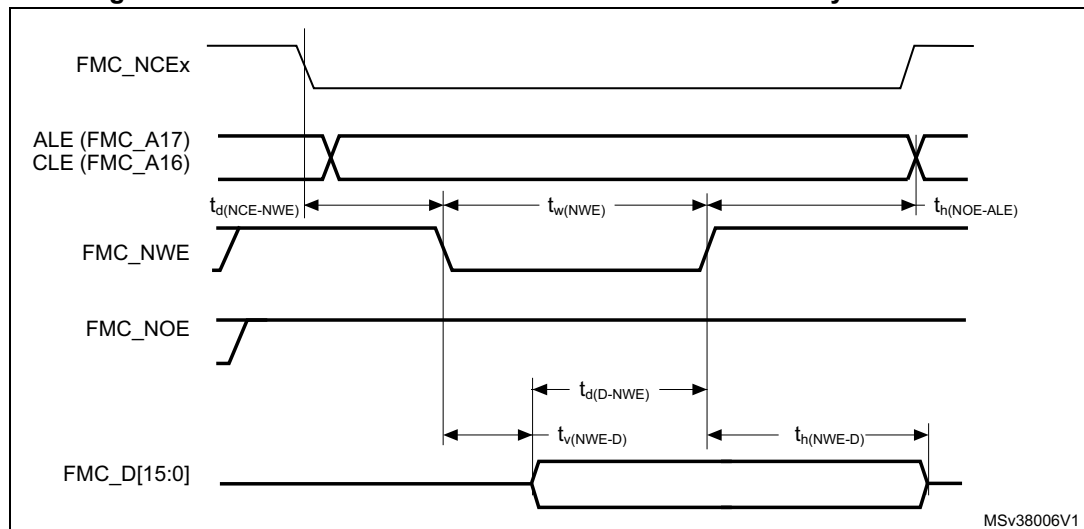


Figure 48. NAND controller waveforms for common memory write access**Table 102. Switching characteristics for NAND Flash read cycles⁽¹⁾⁽²⁾**

Symbol	Parameter	Min	Max	Unit
$T_{w(NOE)}$	FMC_NOE low width	$4T_{HCLK}-1$	$4T_{HCLK}+1$	ns
$T_{su(D-NOE)}$	FMC_D[15-0] valid data before FMC_NOE high	16	-	
$T_{h(NOE-D)}$	FMC_D[15-0] valid data after FMC_NOE high	6	-	
$T_{d(NCE-NOE)}$	FMC_NCE valid before FMC_NOE low	-	$3T_{HCLK}+1$	
$T_{h(NOE-ALE)}$	FMC_NOE high to FMC_ALE invalid	$2T_{HCLK}-2$	-	

1. CL = 30 pF.

2. Guaranteed by characterization results.

Table 103. Switching characteristics for NAND Flash write cycles⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$T_{w(NWE)}$	FMC_NWE low width	$4T_{HCLK}-1$	$4T_{HCLK}+1$	ns
$T_{v(NWE-D)}$	FMC_NWE low to FMC_D[15-0] valid	-	2.5	
$T_{h(NWE-D)}$	FMC_NWE high to FMC_D[15-0] invalid	$3T_{HCLK}-4$	-	
$T_{d(D-NWE)}$	FMC_D[15-0] valid before FMC_NWE high	$5T_{HCLK}-3$	-	
$T_{d(NCE-NWE)}$	FMC_NCE valid before FMC_NWE low	-	$3T_{HCLK}+1$	
$T_{h(NWE-ALE)}$	FMC_NWE high to FMC_ALE invalid	$2T_{HCLK}-2$	-	

1. CL = 30 pF.

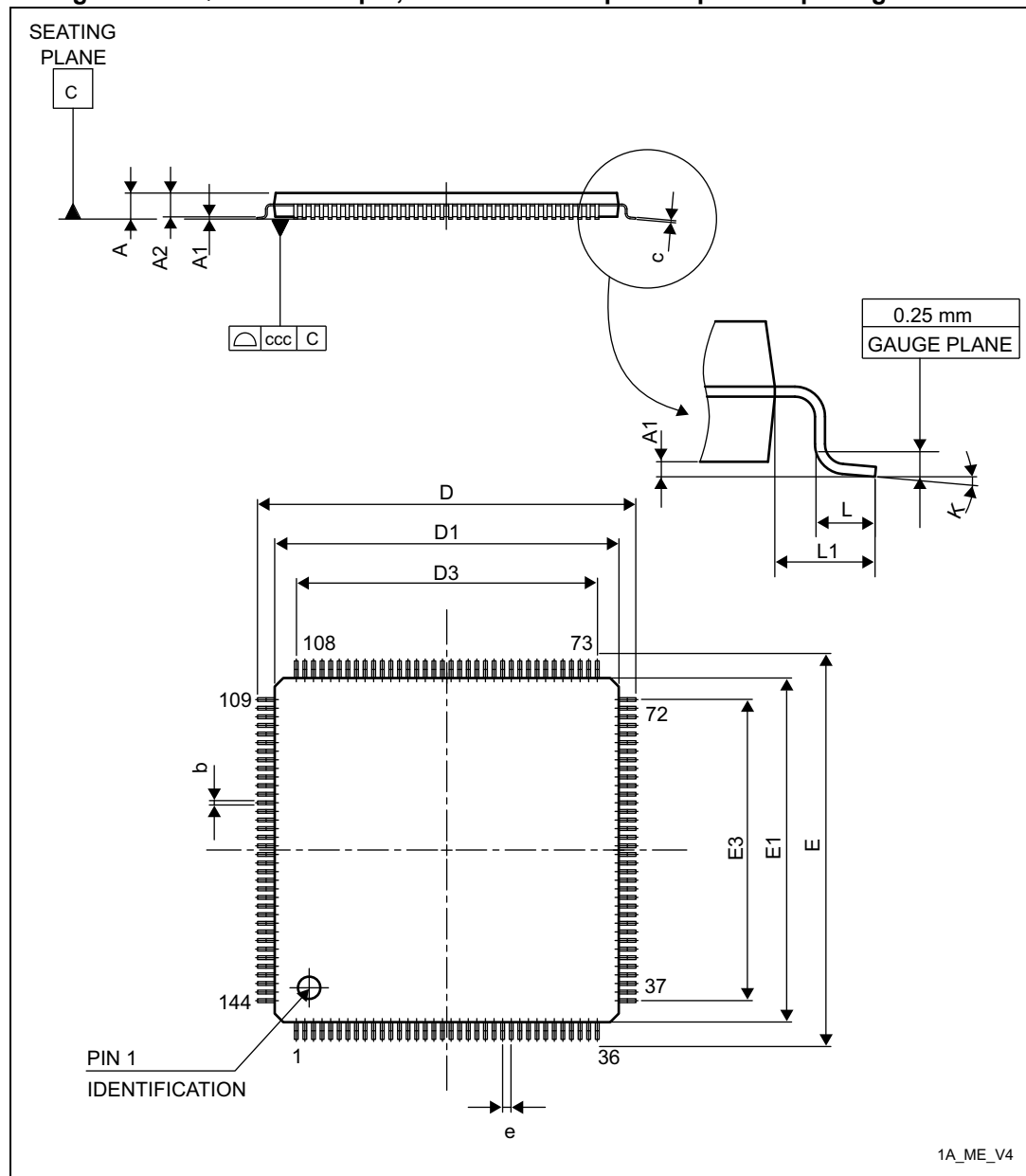
2. Guaranteed by characterization results.

7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.

7.1 LQFP144 package information

Figure 49. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package outline



1. Drawing is not to scale.

Using the values obtained in [Table 113](#) T_{Jmax} is calculated as follows:

– For LQFP64, 45 °C/W

$$T_{Jmax} = 100\text{ °C} + (45\text{ °C/W} \times 134\text{ mW}) = 100\text{ °C} + 6.03\text{ °C} = 106.03\text{ °C}$$

This is above the range of the suffix 6 version parts ($-40 < T_J < 105\text{ °C}$).

In this case, parts must be ordered at least with the temperature range suffix 7 (see [Section 8: Part numbering](#)) unless we reduce the power dissipation in order to be able to use suffix 6 parts.

Refer to [Figure 67](#) to select the required temperature range (suffix 6 or 7) according to your ambient temperature or power requirements.

Figure 67. LQFP64 P_D max vs. T_A

